

**Search Notes**

Application/Control No.

10/664,873

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

TAMAMURA ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12	10/27/2006	DWY
429	13	10/27/2006	DWY
429	17	10/27/2006	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	10/27/2006	DWY